



ALPHA & OMEGA
SEMICONDUCTOR

AO3419

P-Channel Enhancement Mode Field Effect Transistor



General Description

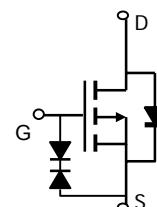
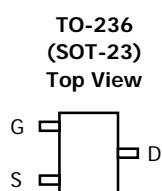
The AO3419/L uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a load switch or in PWM applications. It is ESD protected. AO3419 and AO3419L are electrically identical.

-RoHS Compliant

-AO3419L is Halogen Free

Features

V_{DS} (V) = -20V
 I_D = -3.5 A (V_{GS} = -10V)
 $R_{DS(ON)} < 75m\Omega$ (V_{GS} = -10V)
 $R_{DS(ON)} < 95m\Omega$ (V_{GS} = -4.5V)
 $R_{DS(ON)} < 145m\Omega$ (V_{GS} = -2.5V)
 ESD Rating: 2000V HBM



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current ^A	I_D	-3.5	A
$T_A=70^\circ C$		-2.8	
Pulsed Drain Current ^B	I_{DM}	-15	
Power Dissipation ^A	P_D	1.4	W
$T_A=70^\circ C$		0.9	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	65	90	°C/W
Steady-State		85	125	°C/W
Maximum Junction-to-Lead ^C	$R_{\theta JL}$	43	60	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-16\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		-0.5	-2.5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 10\text{V}$		± 1	± 10	μA
		$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$				μA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	-0.7	-0.9	-1.4	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-15			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-3.5\text{A}$ $T_J=125^\circ\text{C}$		59	75	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-3\text{A}$		83	105	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-1\text{A}$		76	95	$\text{m}\Omega$
		$V_{GS}=-1.8\text{V}, I_D=-0.5\text{A}$		111	145	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-3.5\text{A}$		225		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$	-1	-0.81		V
I_S	Maximum Body-Diode Continuous Current				-2	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-10\text{V}, f=1\text{MHz}$		512	620	pF
C_{oss}	Output Capacitance			77		pF
C_{rss}	Reverse Transfer Capacitance			62		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		9.2	13	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, I_D=-3.5\text{A}$		5.5	6.6	nC
Q_{gs}	Gate Source Charge			0.8		nC
Q_{gd}	Gate Drain Charge			1.9		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-10\text{V}, V_{DS}=-10\text{V}, R_L=2.8\Omega, R_{\text{GEN}}=3\Omega$		5		ns
t_r	Turn-On Rise Time			6.7		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			28		ns
t_f	Turn-Off Fall Time			13.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-3.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		9.8	12	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-3.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		2.7		nC

A: The value of R_{JJA} is measured with the device mounted on 1 in ² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The R_{JJA} is the sum of the thermal impedance from junction to lead R_{JL} and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using <300 μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in ² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

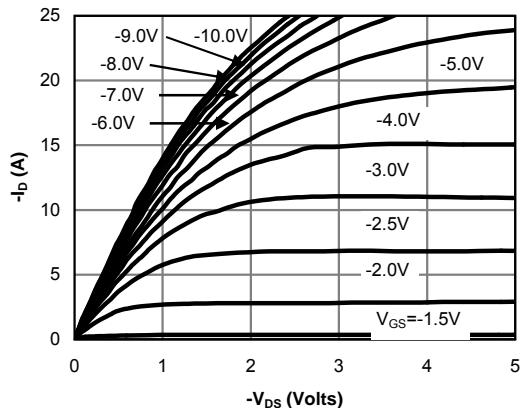


Fig 1: On-Region Characteristics

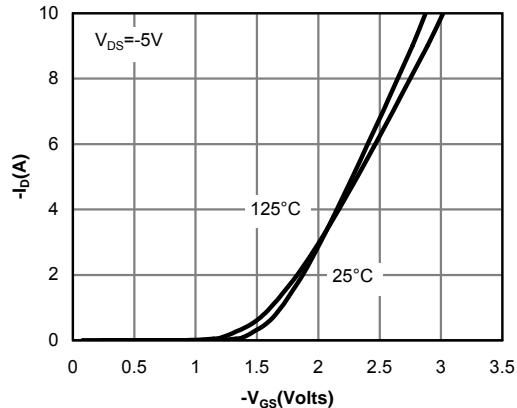


Figure 2: Transfer Characteristics

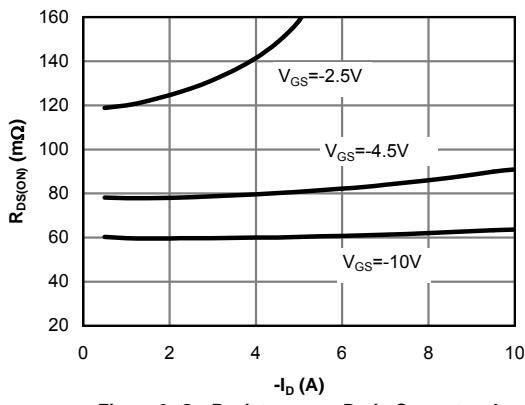


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

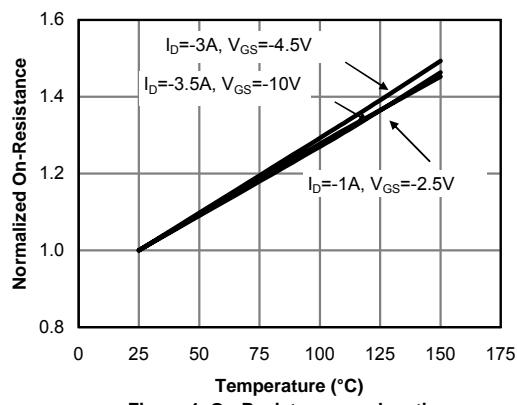


Figure 4: On-Resistance vs. Junction Temperature

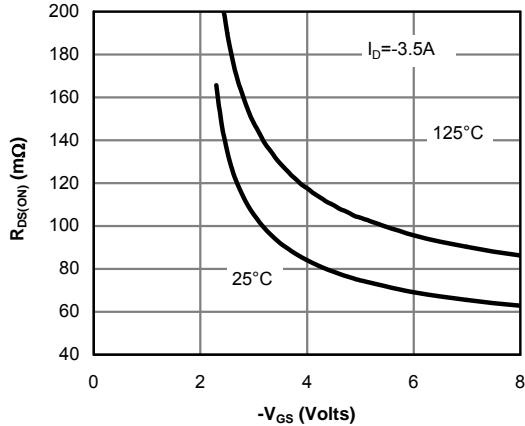


Figure 5: On-Resistance vs. Gate-Source Voltage

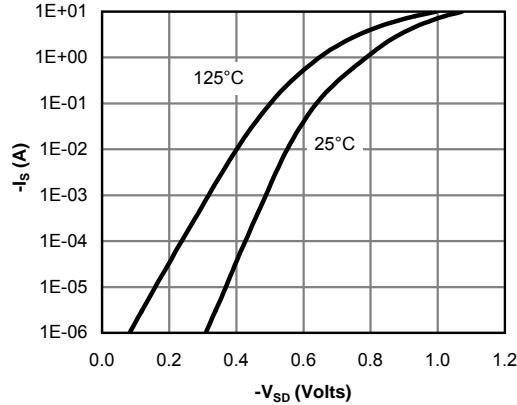


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

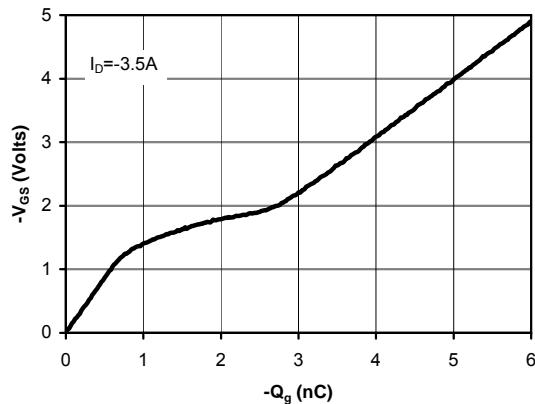


Figure 7: Gate-Charge Characteristics

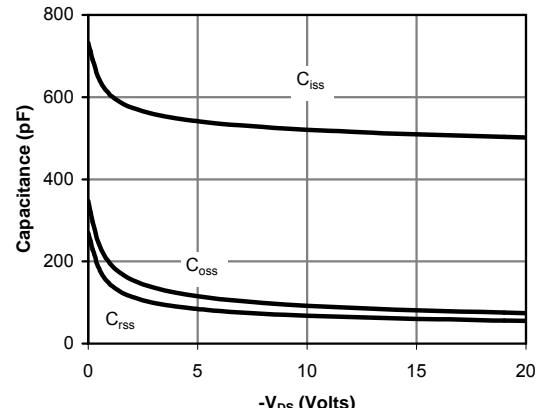


Figure 8: Capacitance Characteristics

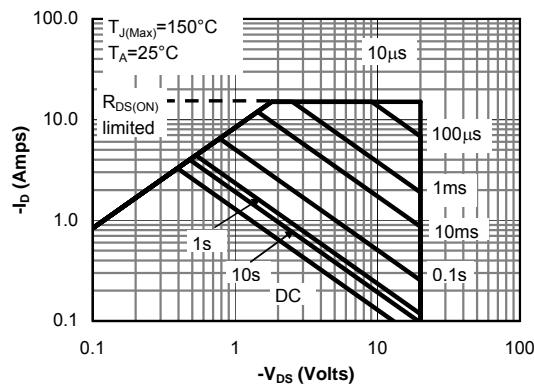


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

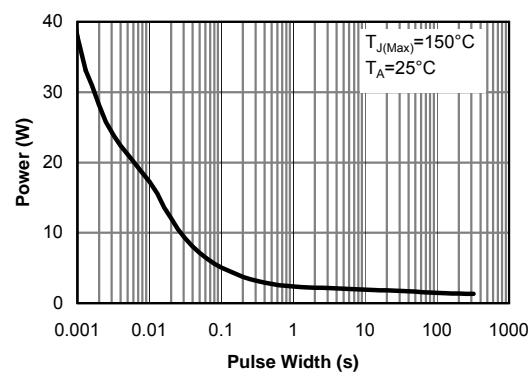


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

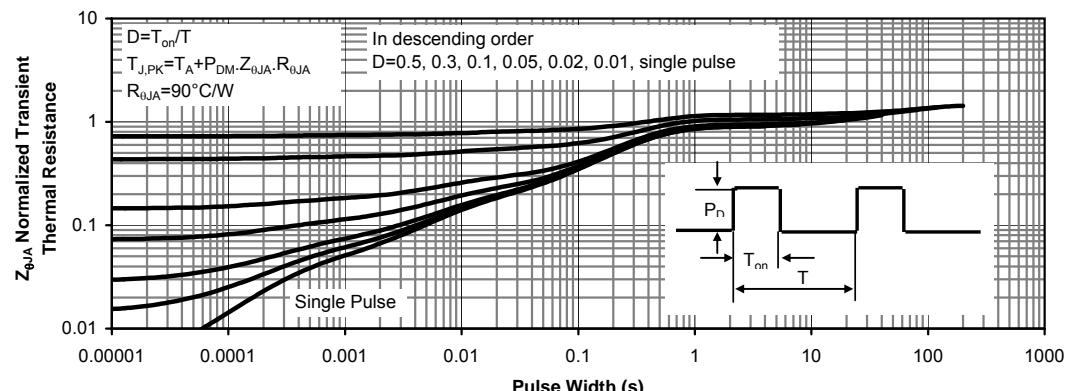


Figure 11: Normalized Maximum Transient Thermal Impedance